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# **Notice of References Cited**

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Application/Control No.	Applicant(s)/l	Patent Under			
09/325,143	Reexamination LEE, CHIN-HUI ET AL.				
Examiner	Art Unit				
Gerald Gauthier	2645	Page 1 of 1			

#### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,742,736	04-1998	Haddock, Nicholas John	704/270
	В	US-6,035,017	03-2000	Fenton et al.	379/88.04
	С	US-			
	D	US-			
	Ε	US-			·
	F	US-			
	G	US-			
	H	US-			
	ı	US-			
	J	US-			
	к	US-		-	
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

	TOREIGN FAILURE					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.